

### Monitor for Aging Effects (Radiation, Total Ionizing Dose, Temperature, Power and Switching Stress)

#### Features:

- In Situ Monitoring of aging effects
  - TID (Total Ionizing Dose)
  - Temperature stress
  - Power stress
  - Switching stress
- Inspection of the functionality for Risk Based Maintenance (safety margins)
- Determination of health status and remaining useful life (RUL)
- Customized control interface, easily adaptable for standard interfaces (e.g. JTAG, SPI, I2C)

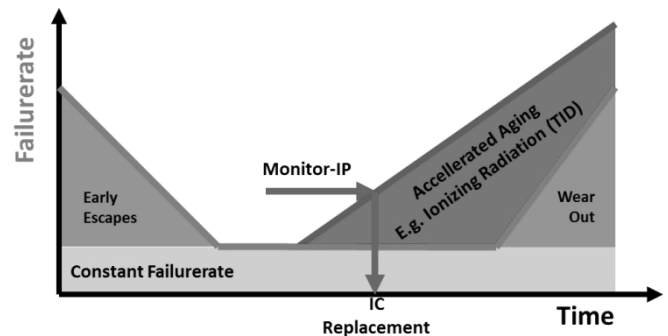


Figure 1 Bathtub Curve

#### Applications:

- Embedded systems, control systems, signal processing and data storage in high radiation environments (e.g. medical equipment, aviation, aerospace, nuclear power plant)
- Monitor delay degradation due to stress (temperature, switching, power etc.) in long-term system applications
- Out of specification applications (e.g. over temperature)

#### Targeted Devices:

- Microsemi
  - SmartFusion2
  - Polarfire
- Xilinx
  - Spartan-7
  - Artix-7
  - Virtex-7
- Others supported upon request

#### Core Deliverables:

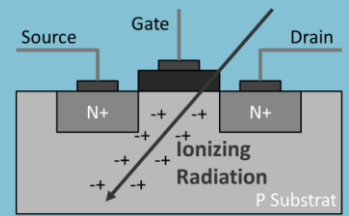
- Encrypted VHDL Soft Core
- VHDL Package
- Test Bench
- Application Example
- VHDL Source Code on request

#### Support:

- Simulation: ModelSim®
- Synthesis: Synplicity®
- Microsemi/Libero®
- Xilinx/Vivado®
- Other tools supported upon request
- Implementation support on request

# Aging\_IP

## Monitor for Aging Effects (TID & Stress)



### Description:

The configurable Aging IP is designed to detect parameter degradation due to ionizing radiation (nuclear plants, accelerators, medical radiation, cosmic rays, aerospace) or temperature, power and switching stress. It covers the following features:

- Delay Chain Output (DCO)
- DCO counters (DCO0, DCO1)
- Duty cycle deviation
- Min/max delay deviations and flags
- User Interface (ports, registers)

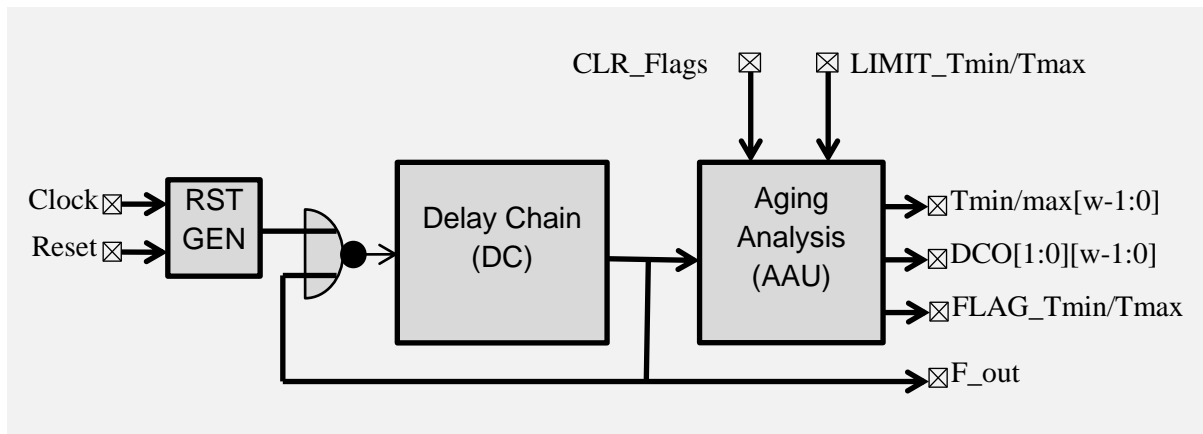


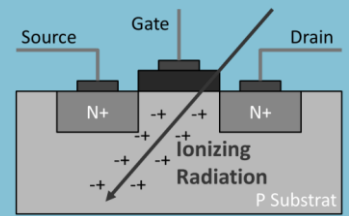
Figure 2 Principle Architecture

The architecture comprises a configurable Delay Chain, a delay analysis block (limits, flags, counters) and a customized user interface for configuration, monitoring and for additional offline analysis.

The aging analysis unit performs timing/frequency measurements and continuous variance analysis and check for min/max limits. The ports of this units can be connected to a User/SW Interface (e.g. SPI) and/or to device IO pins.

# Aging\_IP

## Monitor for Aging Effects (TID & Stress)



### Functional Description

#### Reset Generator (RSTGEN)

The configurable reset generator converts the asynchronous reset signal into a synchronous reset. It initializes the ring oscillator and resets the flipflops.

#### Delay Chain (DC)

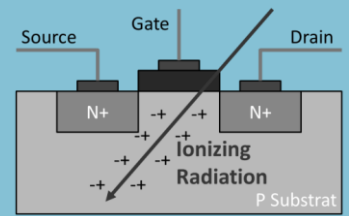
There is a configurable delay chain implemented consisting of  $n$  basic chains. One basic chain consists of  $m$  basic cells. A basic cell consists of 10 basic gates (special implementation feature). The non-inverting output of the delay chain is externally available at port F\_OUT and is internally fed back to the Delay chain input forming a ring oscillator which is initialized by the RSTGEN block. The  $n$  and  $m$  numbers are defined in a VHDL package and characterize the specific ring oscillator frequency.

#### Aging Analysis Unit (AAU)

In situ monitoring of aging effects according TID (Total Ionizing Dose) or electrical and thermal stress by means of inspection of the delay chain and ring oscillator offers Risk Based Maintenance by intelligent timing and frequency measurement and continuous variance analysis. The results are available at the counter outputs DCO[1:0][w-1:0], Tmin/max[w-1:0] and Flag\_Tmin/max. The limits for Tmin/max can be set by the two inputs. If these limits are exceeded, the Flag\_Tmin/max are set and can be cleared by the input CLR\_Flags.

#### Implementation possibilities

The functionality can be implemented as standalone Diagnosis Device (FPGA) embedded on system boards or embedded as IP-core in system chips (ASIC, SOC, ASSP).



### Signal Descriptions

| Signal            | Direction | Description   |
|-------------------|-----------|---|
| clock             | input     | Clock for the IP block (e.g. 200 MHz)               |
| reset             | input     | Asynchronous reset signal                           |
| clr_flags         | input     | Clear all flags                                     |
| limit_tmax[w-1:0] | input     | Limit Tmax (raw number of clock cycles)             |
| limit_tmin[w-1:0] | input     | Limit Tmin (raw number of clock cycles)             |
| f_out             | output    | ROSC output for ext. frequency measurements         |
| dco[1:0][w-1:0]   | output    | DCO counters for high/low period (raw clock cycles) |
| tmax[w-1:0]       | output    | Measured max period (raw clock cycles)              |
| tmin[w-1:0]       | output    | Measured min period (raw clock cycles)              |
| flag_tmax         | output    | Flag if max limit is exceeded                       |
| flag_tmin         | output    | Flag if min limit is exceeded                       |

### Description of Constants (VHDL package)

| Generic       | Type    | Description                                    |
|---------------|---------|--|
| c_td          | time    | average delay per cell                         |
| c_clk_period  | time    | Clock period                                   |
| c_cells       | natural | Number of cells (consisting of 10 basic gates) |
| c_chains      | natural | Number of chains                               |
| c_limit_tmax  | natural | Limit tmax (raw clock cycles)                  |
| c_limit_tmin  | natural | Limit tmin (raw clock cycles)                  |
| c_rst_clks    | natural | Reset length (raw clock cycles)                |
| c_count_width | natural | Width of data/counters                         |
| c_sample_size | natural | Sampling for mean value calculation            |